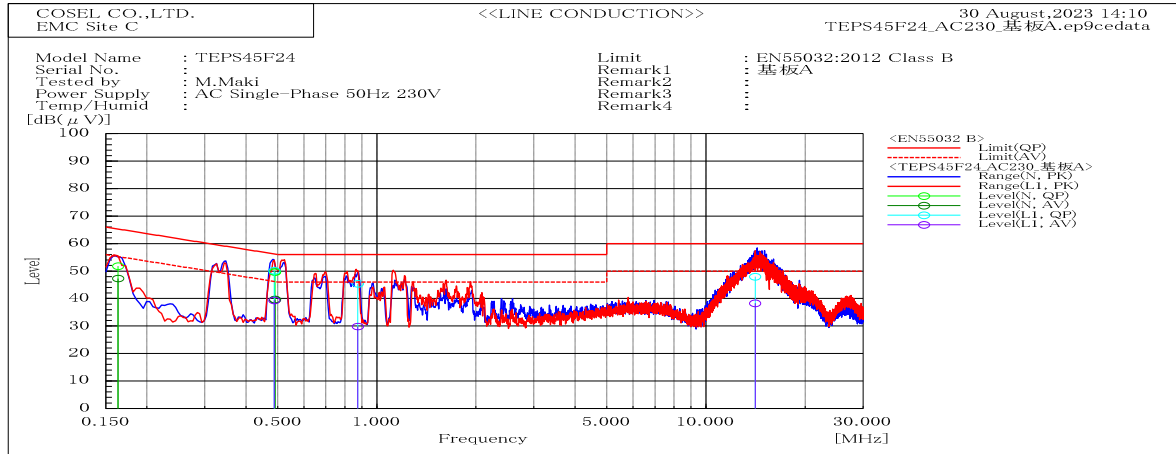
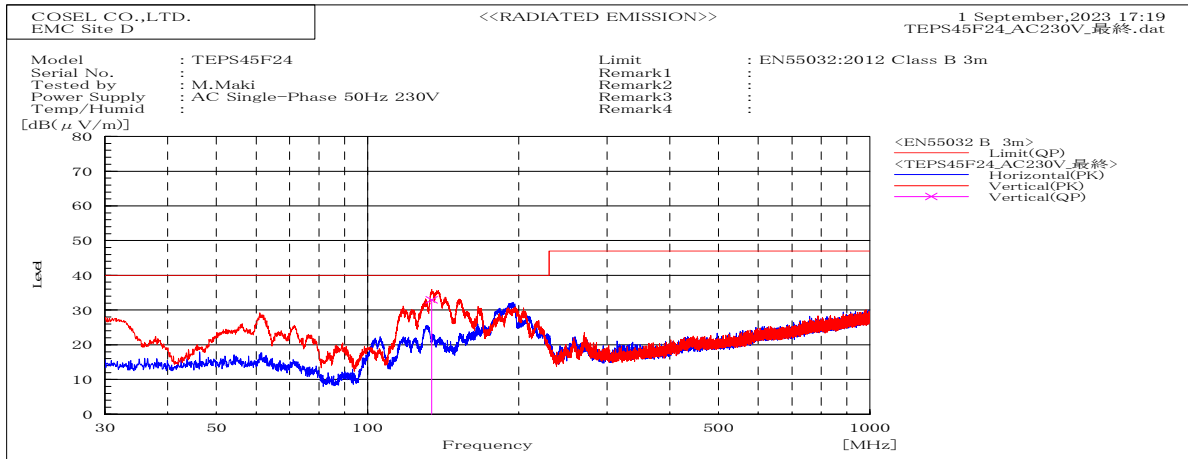


DATA SHEET		Date	12-Oct-23
Model	TEPS45F24	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	M.Maki



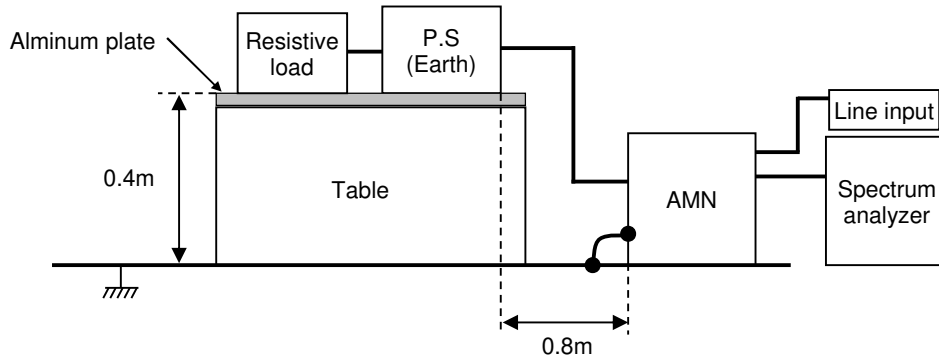
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
0.488	L1	50.1	39.3	56.2	46.2	6.1	6.9	Pass	
0.875	L1	45.4	29.8	56	46	10.6	16.2	Pass	
14.106	L1	47.9	38.3	60	50	12.1	11.7	Pass	
0.164	N	51.8	47.3	65.3	55.3	13.5	8	Pass	
0.49	N	49.7	39.6	56.2	46.2	6.5	6.6	Pass	
0.49	N	49.6	39.5	56.2	46.2	6.6	6.7	Pass	



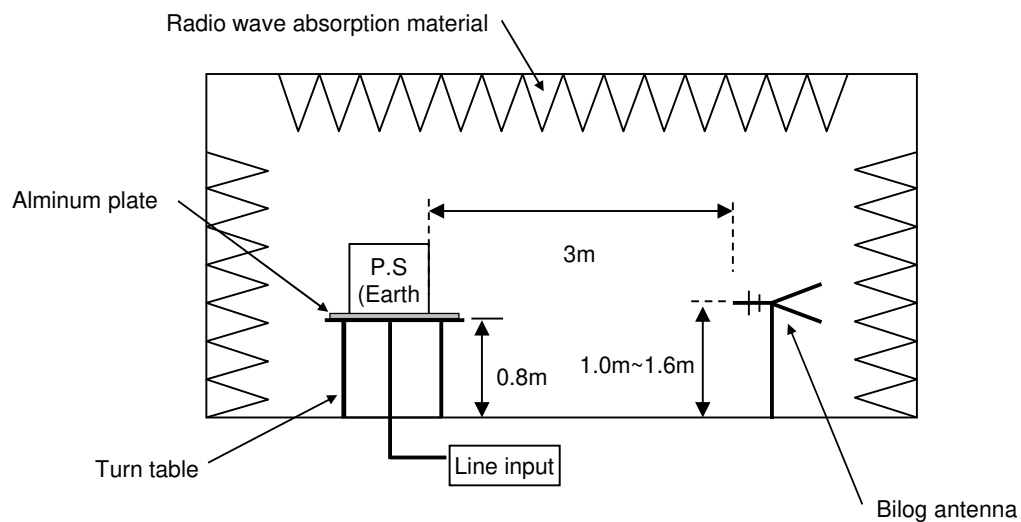
Frequency MHz	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height cm	Angle deg	Remark
			dB(μV/m) QP	dB(μV/m) QP	dB QP				
134.098	V	Stable	33	40	7	Pass	101.5	0	

DATA SHEET		Date	12-Oct-23
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	M.Maki

### 1. Line conduction



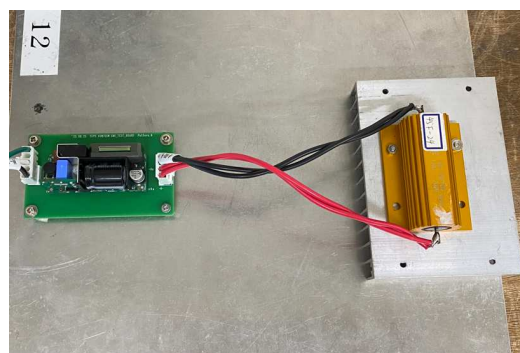
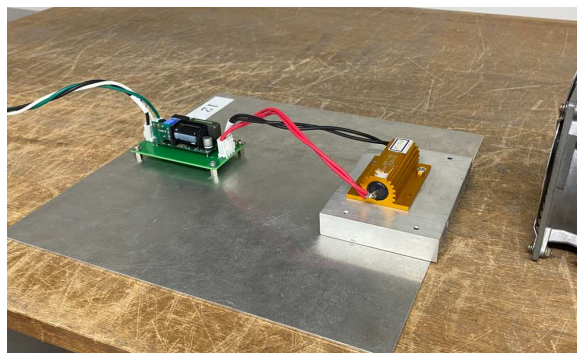
### 2. Radiated emission



## Conditions

Test : EMI  
Model Nam: TEPS45F24

### 1.LINE CONDUCTION



### 2.RADIATED EMISSION

